



**AT-60535**  
Up to 6 GHz Low Noise  
Silicon Bipolar Transistor

### Features

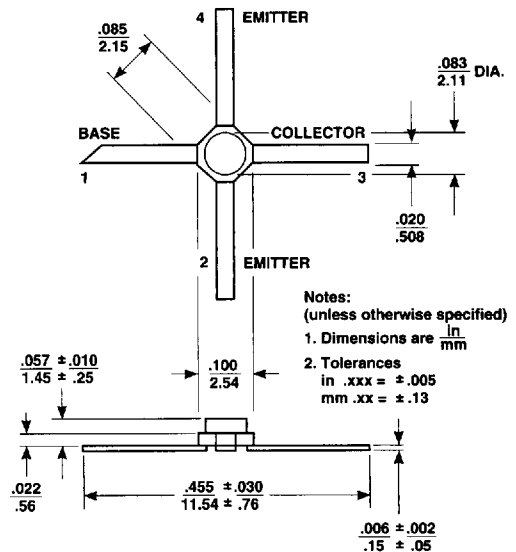
- **Low Bias Current Operation:**
- **Low Noise Figure: 1.8 dB typical at 2.0 GHz  
2.8 dB typical at 4.0 GHz**
- **High Associated Gain: 12.0 dB typical at 2.0 GHz  
7.5 dB typical at 4.0 GHz**
- **High Gain-Bandwidth Product: 8.0 GHz typical fr**
- **Cost Effective Ceramic Microstrip Package**

### Description

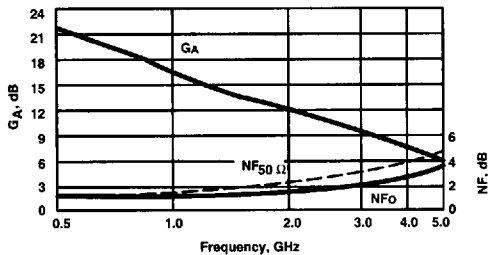
The AT-60535 is a high performance NPN silicon bipolar transistor housed in a cost-effective, microstrip package. This device is designed for use in low noise, wide band amplifier and oscillator applications operating over VHF, UHF and microwave frequencies.

Excellent device uniformity, performance and reliability are produced by the use of ion-implantation, self-alignment techniques, and gold metallization in the fabrication of these devices.

### 35 micro-X Package



NOISE FIGURE AND ASSOCIATED GAIN  
vs. FREQUENCY  
V<sub>CE</sub> = 8 V, I<sub>C</sub> = 2 mA



Noise Parameters: V<sub>CE</sub> = 8 V, I<sub>C</sub> = 2 mA

Freq. GHz	NF <sub>0</sub> dB	Gamma Opt Mag	Ang	Rn/50
1.0	1.4	.50	55	0.32
2.0	1.8	.40	114	0.38
4.0	2.8	.38	-153	0.40

### Electrical Specifications, T<sub>A</sub> = 25°C

Symbol	Parameters and Test Conditions	Units	Min.	Typ.	Max.
NF <sub>0</sub>	Optimum Noise Figure: V <sub>CE</sub> = 8 V, I <sub>C</sub> = 2 mA f = 1.0 GHz f = 2.0 GHz f = 4.0 GHz	dB		1.4 1.8 2.8	2.1
GA	Gain @ NF <sub>0</sub> : V <sub>CE</sub> = 8 V, I <sub>C</sub> = 2 mA f = 1.0 GHz f = 2.0 GHz f = 4.0 GHz	dB	11.0	16.5 12.0 7.5	
IS <sub>21EI</sub> <sup>2</sup>	Insertion Power Gain: V <sub>CE</sub> = 8 V, I <sub>C</sub> = 10 mA f = 2.0 GHz f = 4.0 GHz	dB		11.5 6.0	
P <sub>1</sub> dB	Power Output @ 1 dB Gain Compression. V <sub>CE</sub> = 8 V, I <sub>C</sub> = 10 mA f = 2.0 GHz	dBm		16.0	
G <sub>1</sub> dB	1 dB Compressed Gain: V <sub>CE</sub> = 8 V, I <sub>C</sub> = 10 mA f = 2.0 GHz	dB		11.5	
f <sub>T</sub>	Gain Bandwidth Product: V <sub>CE</sub> = 8 V, I <sub>C</sub> = 10 mA	GHz		8.0	
h <sub>FE</sub>	Forward Current Transfer Ratio. V <sub>CE</sub> = 8 V, I <sub>C</sub> = 10 mA		30	150	300
I <sub>CBO</sub>	Collector Cutoff Current: V <sub>CB</sub> = 8 V	μA			0.2
I <sub>EBO</sub>	Emitter Cutoff Current: V <sub>EB</sub> = 1 V	μA			1.0
CCB	Collector Base Capacitance <sup>1</sup> : V <sub>CB</sub> = 8 V, f = 1 MHz	pF		0.15	

Note 1 For this test the emitter is grounded

**AT-60535**  
**Low Noise Silicon Bipolar Transistor**

**Absolute Maximum Ratings**

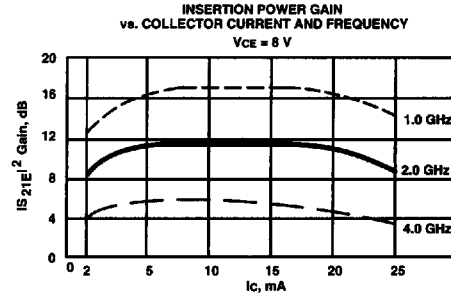
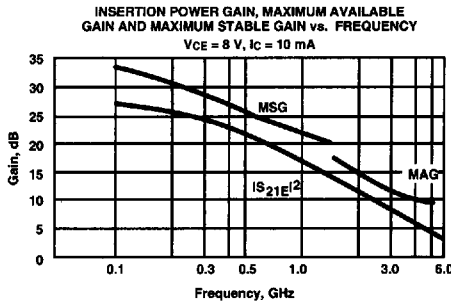
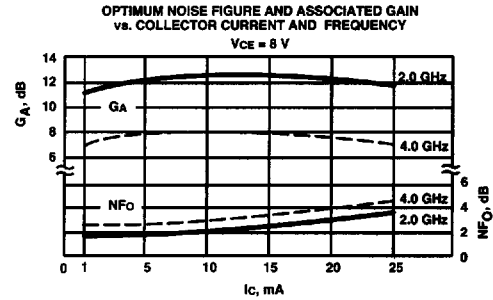
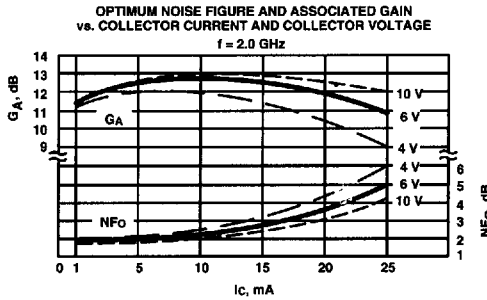
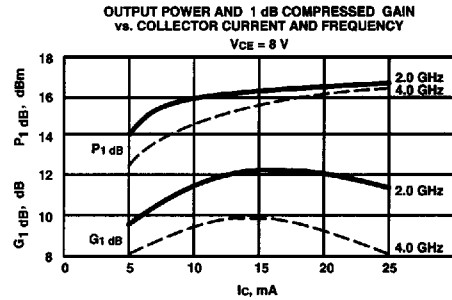
Parameter	Symbol	Absolute Maximum <sup>1</sup>
Emitter-Base Voltage	VEBO	1.5 V
Collector-Base Voltage	VCBO	20 V
Collector-Emitter Voltage	VCEO	12 V
Collector Current	IC	40 mA
Power Dissipation <sup>2,3</sup>	PT	400 mW
Junction Temperature	T <sub>J</sub>	200°C
Storage Temperature <sup>4</sup>	TSTG	-65°C to 200°C

Thermal Resistance<sup>2,5</sup>:  $\theta_{JC} = 225^\circ\text{C/W}$

**Notes:**

1. Operation of this device above any one of these parameters may cause permanent damage.
2. TCASE = 25°C.
3. Derate at 4.4 mW/°C for TC > 110°C.
4. Storage above +150°C may tarnish the leads of this package making it difficult to solder into a circuit. After a device has been soldered into a circuit, it may be safely stored up to 200°C.
5. The small spot size of this technique results in a higher, though more accurate determination of  $\theta_{JC}$  than do alternate methods. See MEASUREMENTS section "Thermal Resistance" for more information.

**Typical Performance, T<sub>A</sub> = 25°C**  
 (unless otherwise noted)



Typical Scattering Parameters: Common Emitter,  $Z_0 = 50 \Omega$

$T_A = 25^\circ\text{C}$ ,  $V_{CE} = 8 \text{ V}$ ,  $I_C = 2 \text{ mA}$

Freq. GHz	S <sub>11</sub>		S <sub>21</sub>			S <sub>12</sub>			S <sub>22</sub>	
	Mag	Ang	dB	Mag	Ang	dB	Mag	Ang	Mag	Ang
0.1	.94	-10	16.6	6.77	171	-39.2	.011	92	.99	-4
0.5	.83	-47	15.3	5.80	139	-27.6	.042	63	.92	-17
1.0	.64	-84	12.7	4.33	109	-23.8	.065	44	.81	-27
1.5	.50	-111	10.6	3.38	90	-22.4	.075	41	.74	-33
2.0	.42	-137	8.7	2.73	74	-21.6	.083	37	.70	-38
2.5	.37	-156	7.5	2.33	64	-21.0	.090	38	.67	-40
3.0	.37	-177	7.4	2.02	51	-20.8	.092	43	.66	-47
3.5	.37	164	5.0	1.77	39	-19.7	.103	41	.66	-56
4.0	.36	148	4.0	1.57	27	-19.2	.110	42	.67	-64
4.5	.37	131	3.0	1.42	17	-18.3	.121	42	.69	-70
5.0	.38	113	2.2	1.29	6	-17.1	.140	43	.69	-76
5.5	.43	93	1.5	1.19	-3	-15.9	.159	39	.69	-82
6.0	.50	80	0.8	1.09	-14	-15.0	.178	36	.66	-91

$T_A = 25^\circ\text{C}$ ,  $V_{CE} = 8 \text{ V}$ ,  $I_C = 10 \text{ mA}$

0.1	.77	-24	27.0	22.31	160	-41.0	.009	76	.96	-8
0.5	.47	-90	22.0	12.51	113	-31.0	.028	58	.72	-22
1.0	.33	-131	17.0	7.08	89	-27.2	.044	60	.63	-25
1.5	.28	-159	13.8	4.90	74	-25.0	.056	57	.60	-28
2.0	.27	176	11.5	3.77	63	-23.0	.070	58	.59	-33
2.5	.28	162	9.9	3.11	56	-21.6	.083	62	.57	-35
3.0	.30	149	8.4	2.64	46	-20.4	.096	60	.56	-43
3.5	.32	136	7.2	2.31	36	-19.1	.111	57	.57	-52
4.0	.33	124	6.2	2.04	26	-17.8	.129	53	.58	-60
4.5	.34	110	5.2	1.83	16	-16.7	.147	50	.60	-67
5.0	.36	95	4.4	1.67	6	-15.6	.166	45	.61	-73
5.5	.41	81	3.7	1.53	-2	-14.9	.180	40	.61	-79
6.0	.49	72	3.0	1.41	-12	-14.2	.196	36	.57	-87

A model for this device is available in the DEVICE MODELS section